

Notice of References Cited	Application/Control No. 10/558,715		Applicant(s)/Patent Under Reexamination FERRETTI ET AL.	
	Examiner MAX SHIKHMAN		Art Unit 2624	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Ramponi, Warped distance for space-variant linear image interpolation, May 1999, IEEE Image Processing, Volume: 8, Issue: 5. pp 629-639
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.